

Applications

Our customised SOI solutions are used in the following fields:

- Advanced pressure sensors
- Accelerometers
- Gyroscopes
- Microfluidics/flow sensors
- RF MEMS
- MOEMs/Optical MEMs
- Optoelectronics
- Smart Power
- Advanced Analog ICs
- Microphones
- Luxury watches

End Markets:

- Telecommunications
- Medical
- Automotive
- Consumer
- Instrumentation

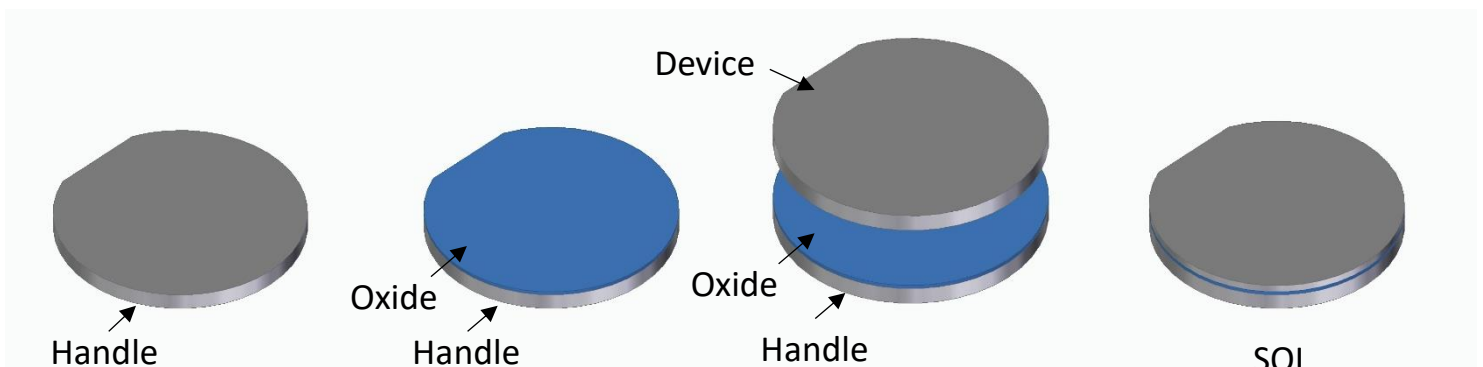
IceMOS Technology is a leading supplier of 100-200mm thick-film Silicon on Insulator wafers for a large range of IC and MEMS applications. With over 20 years' experience in SOI manufacturing, we offer an impressive specification range, which is amongst the widest available in the market.

We have extensive experience in a variety of SOI substrates and our highly skilled applications engineering team is available to assist you to select the optimum combination of parameters for your requirements, ensuring that you receive the perfect custom SOI solution for your application.

By making continuous improvements to our processes in a Lean Six Sigma environment, IceMOS Technology offer world class product quality, competitive cost structure plus rapid turnaround makes IceMOS Technology your ideal SOI partner.



SOI Wafer with <1.5mm edge terrace



SOI Specification

| Parameter | Specification Range | |
|---|--|------------------------|
| Wafer Diameter | 100, 125, 150 mm | 200 mm |
| <i>Handle Layer Specifications</i> | | |
| Handle Thickness | 200–1100 μm | 450–1100 μm |
| Handle Thickness Tolerance | $\pm 5 \mu\text{m}$ | |
| Stack Thickness | 280–1150 μm | |
| Dopant Type | N or P | |
| Doping | N type: Phos, Red Phos, Sb & As P type: Boron | |
| Resistivity | $\leq 0.001 - \geq 10000 \Omega\text{-cm}$ | |
| Growth Method | CZ, MCZ or FZ | |
| Crystal Orientation | $\langle 100 \rangle$, $\langle 111 \rangle$ or $\langle 110 \rangle$ | |
| Backside Finish | Lapped/Etched or Polished | |
| <i>Buried Oxide Specifications</i> | | |
| Thermally Oxidised Buried Oxide Thickness | 0.2 – 4.0 μm grown on Handle, Device or both wafers | |
| <i>Device Layer Specifications</i> | | |
| Device Layer Thickness | $\geq 1.5 \mu\text{m}$ | $\geq 5 \mu\text{m}$ |
| Tolerance | $\pm 0.5 \mu\text{m}$ | $\pm 0.8 \mu\text{m}$ |
| Dopant Type | N or P | |
| Doping | N type: Phos, Red Phos, Sb & As P type: Boron | |
| Resistivity | $\leq 0.001 - \geq 10000 \Omega\text{-cm}$ | |
| Growth Method | CZ, MCZ or FZ | |
| Crystal Orientation | $\langle 100 \rangle$, $\langle 111 \rangle$ or $\langle 110 \rangle$ | |
| Buried Layer Implant | N type or P type | |

The above is a standard IceMOS specification; however, we are always happy to work with our customers to engineer specific solutions. If you would like to discuss an alternative specification, please contact our sales team:
sales@icemostech.com